# PH955L

# N-channel TrenchMOS logic level FET

Rev. 02 — 19 February 2009

**Product data sheet** 

## 1. Product profile

#### 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

#### 1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Suitable for logic level gate drive sources

#### 1.3 Applications

- DC-to-DC convertors
- General purpose power switching
- Motors, lamps and solenoids
- Portable equipment

#### 1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	-	55	V
$I_D$	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 5 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	62.5	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	-	62.5	W
Dynamic	characteristics					
$Q_{GD}$	gate-drain charge	$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 44 \text{ V}; T_j = 25 \text{ °C};$ see Figure 11; see Figure 12	-	16.4	-	nC
Static ch	aracteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V; } I_D = 25 \text{ A;}$ $T_j = 25 \text{ °C; see } \frac{\text{Figure 10}}{\text{ or } 10 \text{ or } 10$	-	6.2	8.3	mΩ



## N-channel TrenchMOS logic level FET

## 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb	D
3	S	source		$G \stackrel{\longleftarrow}{\Longrightarrow} \stackrel{\longleftarrow}{A}$
4	G	gate	q	<u> </u>
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

# 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PH955L	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

#### N-channel TrenchMOS logic level FET

## 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$		-	55	V
$V_{DGR}$	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$		-	55	V
$V_{GS}$	gate-source voltage			-20	20	V
I <sub>D</sub>	drain current	$V_{GS} = 5 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$		-	43.7	Α
		V <sub>GS</sub> = 5 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>		-	62.5	Α
$I_{DM}$	peak drain current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$ ; see Figure 3		-	187	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	62.5	W
T <sub>stg</sub>	storage temperature			-55	150	°C
Tj	junction temperature			-55	150	°C
Source-dr	ain diode					
Is	source current	$T_{mb} = 25  ^{\circ}C$		-	52	Α
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	156	Α
Avalanche	e ruggedness					
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy	$V_{GS}$ = 5 V; $I_D$ = 4.4 A; $V_{sup}$ ≤ 55 V; unclamped; $t_p$ = 0.1 ms; $R_{GS}$ = 50 $\Omega$	[1][2]	-	2	mJ
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 5 V; $T_{j(init)}$ = 25 °C; $I_D$ = 44 A; $V_{sup}$ ≤ 55 V; unclamped; $t_p$ = 0.1 ms; $R_{GS}$ = 50 $\Omega$		-	195	mJ

<sup>[1]</sup> Duty cycle is limited by the maximum junction temperature.

<sup>[2]</sup> Repetitive avalanche failure is not determined simply by thermal effects. Repetitive avalanche transients should only be applied for short bursts, not every switching cycle.

#### N-channel TrenchMOS logic level FET

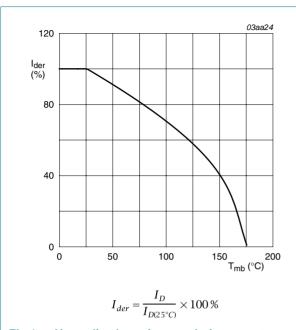


Fig 1. Normalized continuous drain current as a function of mounting base temperature

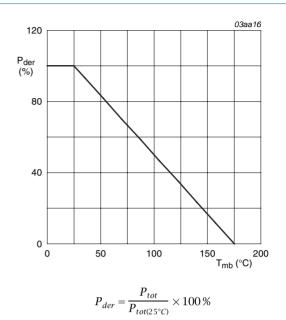
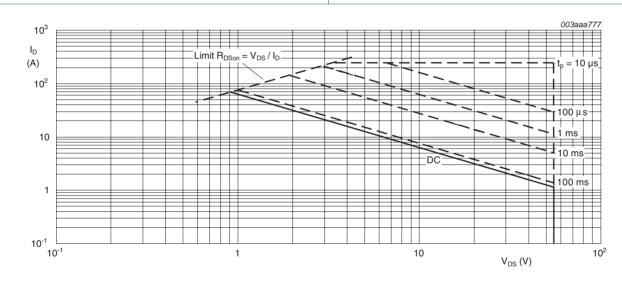


Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25$ °C;  $I_{DM}$  is single pulse

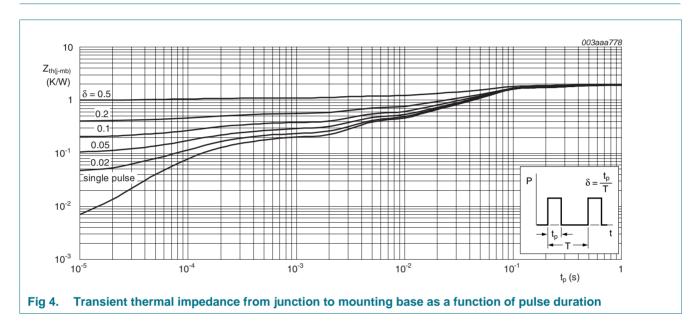
Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

#### N-channel TrenchMOS logic level FET

## 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W



## N-channel TrenchMOS logic level FET

# 6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	50	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	55	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = -55$ °C; see Figure 7; see Figure 8	-	-	2.3	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 150$ °C; see Figure 7; see Figure 8	0.5	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 25$ °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	1	1.5	2	V
DSS	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μΑ
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	500	μΑ
GSS	gate leakage current	$V_{GS} = 15 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
		$V_{GS} = -15 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C}$	-	7.1	9.9	mΩ
	resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 150 \text{ °C};$ see Figure 9	-	-	16	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 10	-	6.2	8.3	mΩ
ynamic	characteristics					
$Q_{G(tot)}$	total gate charge	$I_D = 25 \text{ A}$ ; $V_{DS} = 44 \text{ V}$ ; $V_{GS} = 5 \text{ V}$ ;	-	42	-	nC
$Q_{GS}$	gate-source charge	T <sub>j</sub> = 25 °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	5.7	-	nC
Q <sub>GS1</sub>	pre-threshold gate-source charge		-	4.3	-	nC
$Q_{ m GS2}$	post-threshold gate-source charge		-	1.4	-	nC
$Q_{GD}$	gate-drain charge		-	16.4	-	nC
/ <sub>GS(pl)</sub>	gate-source plateau voltage	$I_D = 25 \text{ A}$ ; $V_{DS} = 44 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see Figure 11; see Figure 12	-	2	-	V
Siss	input capacitance	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	2836	-	pF
oss	output capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 13</u>	-	441	-	pF
Prss	reverse transfer capacitance		-	210	-	pF
d(on)	turn-on delay time	$V_{DS} = 25 \text{ V}; R_L = 1 \Omega; V_{GS} = 5 \text{ V};$	-	18	-	ns
	rise time	$R_{G(ext)} = 4.7 \Omega; T_j = 25 °C$	-	71	-	ns
d(off)	turn-off delay time		-	105	-	ns
	fall time		-	25	-	ns
Source-d	rain diode					
/ <sub>SD</sub>	source-drain voltage	$I_S = 25 \text{ A}$ ; $V_{GS} = 0 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see Figure 14	-	0.85	1.2	V
rr	reverse recovery time	$I_S = 20 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = 0 \text{ V}$ ;	-	62	-	ns
	recovered charge	$V_{DS} = 30 \text{ V}; T_i = 25 \text{ °C}$		48		nC

#### N-channel TrenchMOS logic level FET

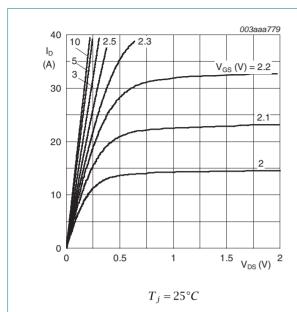
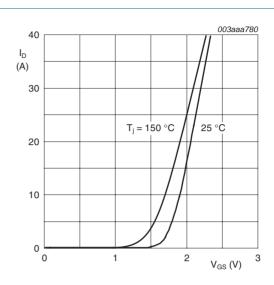


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



 $T_j = 25$ °C and 150°C;  $V_{DS} > I_D \times R_{DSon}$ 

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values

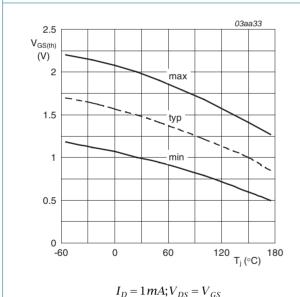
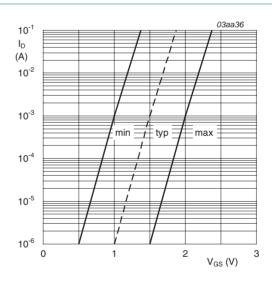


Fig 7. Gate-source threshold voltage as a function of junction temperature



$$T_j = 25 \,^{\circ}C; V_{DS} = V_{GS}$$

Fig 8. Sub-threshold drain current as a function of gate-source voltage

#### N-channel TrenchMOS logic level FET

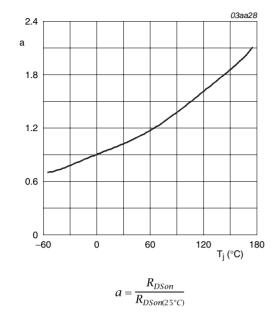
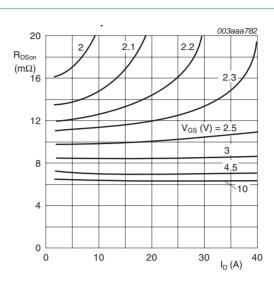
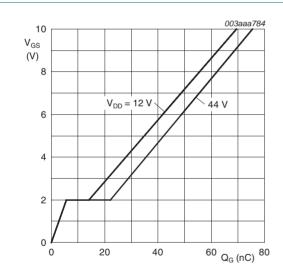


Fig 9. Normalized drain-source on-state resistance factor as a function of junction temperature



 $T_j = 25^{\circ}C$ 

Fig 10. Drain-source on-state resistance as a function of drain current; typical values



 $I_D = 25A; V_{DS} = 12V \, {\rm and} \, 44V$  Fig 11. Gate-source voltage as a function of gate

charge; typical values

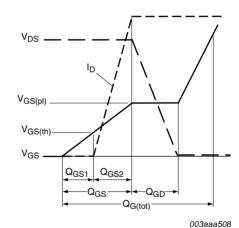


Fig 12. Gate charge waveform definitions

**NXP Semiconductors** 

#### N-channel TrenchMOS logic level FET

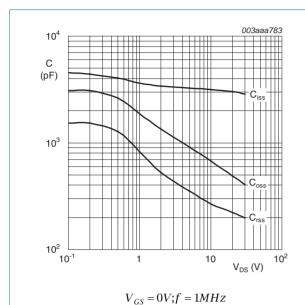
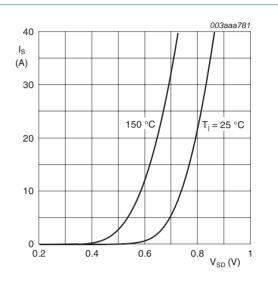


Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

**Product data sheet** 



 $T_i = 25^{\circ} C \text{ and } 150^{\circ} C; V_{GS} = 0V$ 

9 of 13

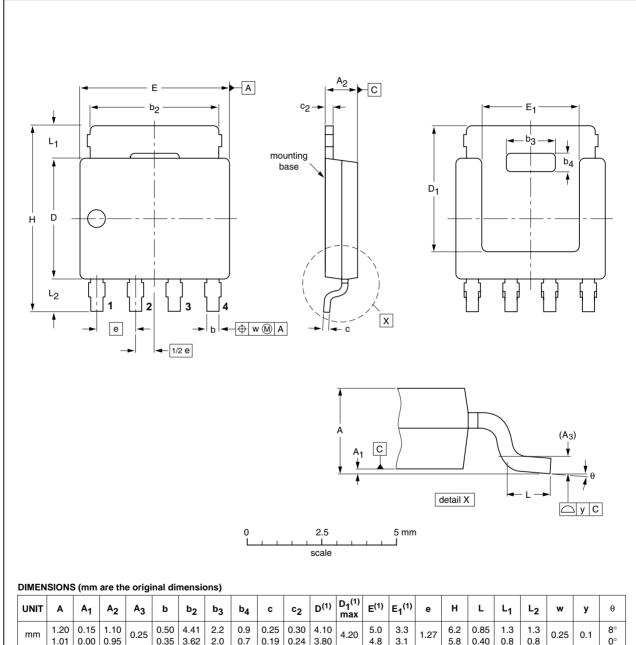
Fig 14. Source current as a function of source-drain voltage; typical values

**NXP Semiconductors** 

## Package outline

#### Plastic single-ended surface-mounted package (LFPAK); 4 leads

**SOT669** 



UNIT	Α	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	b	b <sub>2</sub>	b <sub>3</sub>	b <sub>4</sub>	С	c <sub>2</sub>	D <sup>(1)</sup>	D <sub>1</sub> <sup>(1)</sup> max	E <sup>(1)</sup>	E <sub>1</sub> <sup>(1)</sup>	е	Н	L	L <sub>1</sub>	L <sub>2</sub>	w	у	θ
mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19		4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

#### Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE	
SOT669		MO-235			<del>04-10-13</del> 06-03-16	

Fig 15. Package outline SOT669 (LFPAK)

© NXP B.V. 2009. All rights reserved.

## N-channel TrenchMOS logic level FET

11 of 13

## 8. Revision history

#### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes					
PH955L_2	20090219	Product data sheet	-	PH955L_1					
Modifications:	<ul> <li>The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors.</li> </ul>								
	<ul> <li>Legal texts</li> </ul>	have been adapted to the	new company name whe	ere appropriate.					
PH955L_1 (9397 750 14557)	20050301	Product data sheet	-	-					

#### N-channel TrenchMOS logic level FET

### 9. Legal information

#### 9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

#### 9.2 Definitions

**Draft** — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

#### 9.3 Disclaimers

**General** — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

**Applications** — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

**Quick reference data** — The Quick reference data is an extract of the product data given in the Limiting values and Characteristics sections of this document, and as such is not complete, exhaustive or legally binding.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at <a href="http://www.nxp.com/profile/terms">http://www.nxp.com/profile/terms</a>, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

**No offer to sell or license** — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

#### 9.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

TrenchMOS — is a trademark of NXP B.V.

#### 10. Contact information

For more information, please visit: <a href="http://www.nxp.com">http://www.nxp.com</a>

For sales office addresses, please send an email to: salesaddresses@nxp.com

**PH955L NXP Semiconductors** 

#### N-channel TrenchMOS logic level FET

## 11. Contents

1	Product profile	.1
1.1	General description	. 1
1.2	Features and benefits	. 1
1.3	Applications	. 1
1.4	Quick reference data	. 1
2	Pinning information	.2
3	Ordering information	.2
4	Limiting values	.3
5	Thermal characteristics	.5
6	Characteristics	6
7	Package outline	0
8	Revision history1	1
9	Legal information1	2
9.1	Data sheet status	2
9.2	Definitions1	2
9.3	Disclaimers	2
9.4	Trademarks1	2
10	Contact information	1

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.



